

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: S3-04P03410	Applic. No. Concurrently herewith
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Applicant <b>Klaus Heimerl, et al.</b>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.97(b)(1))		Filing Date <b>December 15, 2005</b>	Group Art Unit

EXAMINE R INITIALS		PATENT NO.	DATE	PATENTEE	<del>CLASS</del>	<del>Sub CLASS</del>	FILING DATE
/TN/	A	6,196,580 B1	03/2001	Eberle, et al.			
	B	2002/0033755 A1	03/2002	Ishizaki, et al.			
	C	2002/0180596 A1	12/2002	Mattes, et al.			
	D	6,516,278 B1	02/2003	Ishizaki, et al.			
	E	6,600,412 B2	07/2003	Ishizaki, et al.			
	F	2003/0156036 A1	08/2003	Stuetzler			
	G	2003/0164755 A1	09/2003	Moritz, et al.			
↓	H	6,693,549 B2	02/2004	Stuetzler			
/TN/	I	6,784,792 B2	08/2004	Mattes, et al.			

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	<del>CLASS</del>	<del>Sub CLASS</del>	TRANSL. YES NO
/TN/	J	WO 03/082639 A1	10/2003	WIPO			
	K	DE 197 18 803 C1	10/1998	Germany			
	L	DE 197 36 840 A1	02/1999	Germany			
	M	DE 198 51 981 A1	05/2000	Germany			
	N	DE 100 45 698 A1	05/2001	Germany			
↓	O	DE 100 03 992 A1	08/2001	Germany			
/TN/	P	DE 100 23 588 A1	11/2001	Germany			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER	/Tan Q. Nguyen/	DATE CONSIDERED	09/17/2008
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: <b>10/561125</b> S3-04P03410	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Applicant <b>Klaus Heimerl, et al.</b>	
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	A						
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	E						
	F						
	G						
	H						
	I						

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	<del>CLASS</del>	<del>SUB CLASS</del>	TRANSL. YES   NO
/TN/	J	DE 100 30 465 A1	01/2002	Germany			
	K	DE 100 39 755 A1	02/2002	Germany			
	L	DE 100 16 142 A1	04/2002	Germany			
	M	DE 101 45 698 A1	05/2002	Germany			
	N	DE 101 13 720 A1	09/2002	Germany			
	O	DE 102 43 508 A1	04/2004	Germany			
↓	P	GB 2 376 118 A	12/2002	England			
/TN/	Q	JP 2000- 25562	01/2000	Japan			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


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